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Substitute for form 1449A/B/PTO  <b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  <i>(Use as many sheets as necessary)</i>				<i>Complete if Known</i>	
				Application Number	09/851,952-Conf. #4043
				Filing Date	May 9, 2001
				First Named Inventor	Theodore H. Fedynyshyn
				Art Unit	1752
				Examiner Name	A. Walke
Sheet	1	of	1	Attorney Docket Number	101328-0151

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code <sup>2</sup> (if known)			
ACW	AA	US-6,063,542	05-16-2000	Hyeon et al.	

FOREIGN PATENT DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Country Code <sup>3</sup> -Number <sup>4</sup> -Kind Code <sup>5</sup> (if known)			
ACW	BA	EP-0 628 876-A1	12-14-1994	International Business Machines Corporation	
	BB	EP-0 789 279-A1	08-13-1997	Wako Pure Chemical Industries, Ltd.	
	BC	EP-0 932 082-A2	07-28-1999	International Business Machines Corporation	
	BD	JP-2000-191732-A1	07-11-2000	Samsung Electronics Co., Ltd.	
V	BE	JP-2000-267287-A1	09-29-2000	Fuji Photo Film Co., Ltd.	
ACW	BF	DE-4 207 261-A1	09-09-1993	Hoechst AG	

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. <sup>1</sup>Applicant's unique citation designation number (optional). <sup>2</sup>See Kinds Codes of USPTO Patent Documents at [www.uspto.gov](http://www.uspto.gov) or MPEP 901.04. <sup>3</sup>Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup>For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup>Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. <sup>6</sup>Applicant is to place a check mark here if English language Translation is attached.

NON PATENT LITERATURE DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.			
ACW	CA	Reynolds, Geoffrey W., "Factors contributing to sidewall roughness in a positive-tone, chemically amplified resist exposed by x-ray lithography." J. Vac. Sci. Technol. B 17(2) (March/April 1999) pp. 334-344.			
ACW	CB	Database WPI, Section Ch, Week 199809, Derwent Publications Ltd., London, GB; Class A89, AN 1998-096984, XP-002192927 & JP 09 325473 A (Nippon Gosei Gomu KK), 16 December 1997 (1997-12-16)			

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Examiner Signature	<i>Amber C. Walke</i>	Date Considered	4/7/05
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